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Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	50MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (1)
SATA	-
USB	USB 1.x (1)
Voltage - I/O	3.3V
Operating Temperature	-40°C ~ 95°C (TA)
Security Features	-
Package / Case	256-BBGA
Supplier Device Package	256-PBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc850srcvr50bu

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Overview

The CPM of the MPC850 supports up to seven serial channels, as follows:

- One or two serial communications controllers (SCCs). The SCCs support Ethernet, ATM (MPC850SR and MPC850DSL), HDLC and a number of other protocols, along with a transparent mode of operation.
- One USB channel
- Two serial management controllers (SMCs)
- One I²C port
- One serial peripheral interface (SPI).

Table 1 shows the functionality supported by the members of the MPC850 family.

Part	Number of SCCs Supported	Ethernet Support	ATM Support	USB Support	Multi-channel HDLC Support	Number of PCMCIA Slots Supported
MPC850	1	Yes	-	Yes	-	1
MPC850DE	2	Yes	-	Yes	-	1
MPC850SR	2	Yes	Yes	Yes	Yes	1
MPC850DSL	2	Yes	Yes	Yes	No	1

Table 1. MPC850 Functionality Matrix

Additional documentation may be provided for parts listed in Table 1.



 θ_{IA} = Package thermal resistance, junction to ambient, °C/W

 $\begin{aligned} \mathbf{P}_{\mathrm{D}} &= \mathbf{P}_{\mathrm{INT}} + \mathbf{P}_{\mathrm{I/O}} \\ \mathbf{P}_{\mathrm{INT}} &= \mathbf{I}_{\mathrm{DD}} \ge \mathbf{V}_{\mathrm{DD}}, \text{watts}\text{---chip internal power} \end{aligned}$

 $P_{I/O}$ = Power dissipation on input and output pins—user determined

For most applications $P_{I/O} < 0.3 \bullet P_{INT}$ and can be neglected. If $P_{I/O}$ is neglected, an approximate relationship between P_D and T_I is:

 $P_{\rm D} = K \div (T_{\rm I} + 273^{\circ} \rm C)(2)$

Solving equations (1) and (2) for K gives:

 $\mathbf{K} = \mathbf{P}_{\mathrm{D}} \bullet (\mathbf{T}_{\mathrm{A}} + 273^{\circ}\mathrm{C}) + \mathbf{\theta}_{\mathrm{JA}} \bullet \mathbf{P}_{\mathrm{D}}^{2}(3)$

where K is a constant pertaining to the particular part. K can be determined from equation (3) by measuring P_D (at equilibrium) for a known T_A . Using this value of K, the values of P_D and T_J can be obtained by solving equations (1) and (2) iteratively for any value of T_A .

5.1 Layout Practices

Each V_{CC} pin on the MPC850 should be provided with a low-impedance path to the board's supply. Each GND pin should likewise be provided with a low-impedance path to ground. The power supply pins drive distinct groups of logic on chip. The V_{CC} power supply should be bypassed to ground using at least four 0.1 µF by-pass capacitors located as close as possible to the four sides of the package. The capacitor leads and associated printed circuit traces connecting to chip V_{CC} and GND should be kept to less than half an inch per capacitor lead. A four-layer board is recommended, employing two inner layers as V_{CC} and GND planes.

All output pins on the MPC850 have fast rise and fall times. Printed circuit (PC) trace interconnection length should be minimized in order to minimize undershoot and reflections caused by these fast output switching times. This recommendation particularly applies to the address and data busses. Maximum PC trace lengths of six inches are recommended. Capacitance calculations should consider all device loads as well as parasitic capacitances due to the PC traces. Attention to proper PCB layout and bypassing becomes especially critical in systems with higher capacitive loads because these loads create higher transient currents in the V_{CC} and GND circuits. Pull up all unused inputs or signals that will be inputs during reset. Special care should be taken to minimize the noise levels on the PLL supply pins.

6 Bus Signal Timing

Table 6 provides the bus operation timing for the MPC850 at 50 MHz, 66 MHz, and 80 MHz. Timing information for other bus speeds can be interpolated by equation using the MPC850 Electrical Specifications Spreadsheet found at http://www.mot.com/netcomm.

The maximum bus speed supported by the MPC850 is 50 MHz. Higher-speed parts must be operated in half-speed bus mode (for example, an MPC850 used at 66 MHz must be configured for a 33 MHz bus).

The timing for the MPC850 bus shown assumes a 50-pF load. This timing can be derated by 1 ns per 10 pF. Derating calculations can also be performed using the MPC850 Electrical Specifications Spreadsheet.

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Table 6.	Bus	Operation	Timing	1
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	.	50 I	MHz	66 I	MHz	80 MHz			Cap Load	
Num	Characteristic	Min	Max	Min	Max	Min	Max	FFACT	(default 50 pF)	Unit
B1	CLKOUT period	20	_	30.30	_	25	_	_		ns
B1a	EXTCLK to CLKOUT phase skew (EXTCLK > 15 MHz and MF <= 2)	-0.90	0.90	-0.90	0.90	-0.90	0.90	_	50.00	ns
B1b	EXTCLK to CLKOUT phase skew (EXTCLK > 10 MHz and MF < 10)	-2.30	2.30	-2.30	2.30	-2.30	2.30	—	50.00	ns
B1c	CLKOUT phase jitter (EXTCLK > 15 MHz and MF <= 2) 2	-0.60	0.60	-0.60	0.60	-0.60	0.60	_	50.00	ns
B1d	CLKOUT phase jitter ²	-2.00	2.00	-2.00	2.00	-2.00	2.00	—	50.00	ns
B1e	CLKOUT frequency jitter (MF < 10) ²	—	0.50	—	0.50	—	0.50	_	50.00	%
B1f	CLKOUT frequency jitter (10 < MF < 500) 2	—	2.00	—	2.00	_	2.00	—	50.00	%
B1g	CLKOUT frequency jitter (MF > 500) ²	_	3.00	_	3.00	_	3.00	_	50.00	%
B1h	Frequency jitter on EXTCLK ³	—	0.50	—	0.50	—	0.50	—	50.00	%
B2	CLKOUT pulse width low	8.00		12.12	—	10.00		—	50.00	ns
B3	CLKOUT width high	8.00	_	12.12	—	10.00	_	—	50.00	ns
B4	CLKOUT rise time	—	4.00	—	4.00	—	4.00	—	50.00	ns
B5	CLKOUT fall time	_	4.00	_	4.00	—	4.00	—	50.00	ns
B7	CLKOUT to A[6–31], RD/WR, BURST, D[0–31], DP[0–3] invalid	5.00	—	7.58	—	6.25	_	0.250	50.00	ns
B7a	CLKOUT to TSIZ[0–1], REG, RSV, AT[0–3], BDIP, PTR invalid	5.00		7.58	_	6.25	_	0.250	50.00	ns
B7b	CLKOUT to BR, BG, FRZ, VFLS[0–1], VF[0–2] IWP[0–2], LWP[0–1], STS invalid ⁴	5.00		7.58	_	6.25	_	0.250	50.00	ns
B8	CLKOUT to A[6–31], RD/WR, BURST, D[0–31], DP[0–3] valid	5.00	11.75	7.58	14.33	6.25	13.00	0.250	50.00	ns
B8a	CLKOUT to TSIZ[0-1], REG, RSV, AT[0-3] BDIP, PTR valid	5.00	11.75	7.58	14.33	6.25	13.00	0.250	50.00	ns
B8b	CLKOUT to BR, BG, VFLS[0–1], VF[0–2], IWP[0–2], FRZ, LWP[0–1], STS valid ⁴	5.00	11.74	7.58	14.33	6.25	13.00	0.250	50.00	ns



[
Num	Characteristic	50 MHz 66 MHz Characteristic		80	MHz	FFACT	Cap Load (default	Unit		
-		Min	Max	Min	Max	Min	Max	_	50 pF)	
B28c	CLKOUT falling edge to WE[0–3] negated GPCM write access TRLX = 0,1 CSNT = 1 write access TRLX = 0, CSNT = 1, EBDF = 1	7.00	14.00	11.00	18.00	9.00	16.00	0.375	50.00	ns
B28d	CLKOUT falling edge to \overline{CS} negated GPCM write access TRLX = 0,1 CSNT = 1, ACS = 10 or ACS = 11, EBDF = 1	_	14.00	_	18.00	_	16.00	0.375	50.00	ns
B29	$\overline{WE[0-3]}$ negated to D[0-31], DP[0-3] high-Z GPCM write access, CSNT = 0	3.00	_	6.00	_	4.00	_	0.250	50.00	ns
B29a	WE[0–3] negated to D[0–31], DP[0–3] high-Z GPCM write access, TRLX = 0 CSNT = 1, EBDF = 0	8.00	_	13.00	_	11.00	_	0.500	50.00	ns
B29b	CS negated to D[0–31], DP[0–3], high-Z GPCM write access, ACS = 00, TRLX = 0 & CSNT = 0	3.00		6.00		4.00		0.250	50.00	ns
B29c	$\overline{\text{CS}}$ negated to D[0–31], DP[0–3] high-Z GPCM write access, TRLX = 0, CSNT = 1, ACS = 10 or ACS = 11, EBDF = 0	8.00		13.00		11.00		0.500	50.00	ns
B29d	WE[0-3] negated to D[0-31], DP[0-3] high-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 0	28.00		43.00		36.00		1.500	50.00	ns
B29e	CS negated to D[0–31], DP[0–3] high-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10 or ACS = 11, EBDF = 0	28.00		43.00		36.00		1.500	50.00	ns
B29f	WE[0–3] negated to D[0–31], DP[0–3] high-Z GPCM write access TRLX = 0, CSNT = 1, EBDF = 1	5.00		9.00		7.00		0.375	50.00	ns
B29g	CS negated to D[0–31], DP[0–3] high-Z GPCM write access TRLX = 0, CSNT = 1, ACS = 10 or ACS = 11, EBDF = 1	5.00		9.00		7.00		0.375	50.00	ns

Table 6.	Bus Operation	Timing ¹	(continued)
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Num	Characteristic	50 I	MHz	66 MHz		80 MHz		80 MHz		FFACT	Cap Load (default	Unit
Num	Unaracteristic	Min	Max	Min	Max	Min	Max	11401	50 pF)	onne		
B42	CLKOUT rising edge to \overline{TS} valid (hold time)	2.00	_	2.00	_	2.00	_	_	50.00	ns		
B43	AS negation to memory controller signals negation	_	TBD	_	TBD	TBD	_	—	50.00	ns		

 Table 6. Bus Operation Timing ¹ (continued)

The minima provided assume a 0 pF load, whereas maxima assume a 50pF load. For frequencies not marked on the part, new bus timing must be calculated for all frequency-dependent AC parameters. Frequency-dependent AC parameters are those with an entry in the FFactor column. AC parameters without an FFactor entry do not need to be calculated and can be taken directly from the frequency column corresponding to the frequency marked on the part. The following equations should be used in these calculations.

For a frequency F, the following equations should be applied to each one of the above parameters: For minima:

$$D = \frac{FFACTOR \times 1000}{F} + (D_{50} - 20 \times FFACTOR)$$

For maxima:

$$D = \frac{FFACTOR \times 1000}{F} + \frac{(D_{50} - 20 \times FFACTOR)}{F} + \frac{1 ns(CAP \ LOAD - 50) / 10}{F}$$

where:

D is the parameter value to the frequency required in ns

F is the operation frequency in MHz

D₅₀ is the parameter value defined for 50 MHz

CAP LOAD is the capacitance load on the signal in question.

FFACTOR is the one defined for each of the parameters in the table.

- ² Phase and frequency jitter performance results are valid only if the input jitter is less than the prescribed value.
- ³ If the rate of change of the frequency of EXTAL is slow (i.e. it does not jump between the minimum and maximum values in one cycle) or the frequency of the jitter is fast (i.e., it does not stay at an extreme value for a long time) then the maximum allowed jitter on EXTAL can be up to 2%.
- ⁴ The timing for BR output is relevant when the MPC850 is selected to work with external bus arbiter. The timing for BG output is relevant when the MPC850 is selected to work with internal bus arbiter.
- ⁵ The setup times required for TA, TEA, and BI are relevant only when they are supplied by an external device (and not when the memory controller or the PCMCIA interface drives them).
- ⁶ The timing required for BR input is relevant when the MPC850 is selected to work with the internal bus arbiter. The timing for BG input is relevant when the MPC850 is selected to work with the external bus arbiter.
- ⁷ The D[0–31] and DP[0–3] input timings B20 and B21 refer to the rising edge of the CLKOUT in which the TA input signal is asserted.
- ⁸ The D[0:31] and DP[0:3] input timings B20 and B21 refer to the falling edge of CLKOUT. This timing is valid only for read accesses controlled by chip-selects controlled by the UPM in the memory controller, for data beats where DLT3 = 1 in the UPM RAM words. (This is only the case where data is latched on the falling edge of CLKOUT.
- ⁹ The timing B30 refers to \overline{CS} when ACS = '00' and to $\overline{WE[0:3]}$ when CSNT = '0'.
- ¹⁰ The signal UPWAIT is considered asynchronous to CLKOUT and synchronized internally. The timings specified in B37 and B38 are specified to enable the freeze of the UPM output signals.
- ¹¹ The $\overline{\text{AS}}$ signal is considered asynchronous to CLKOUT.



Figure 4 provides the timing for the synchronous output signals.

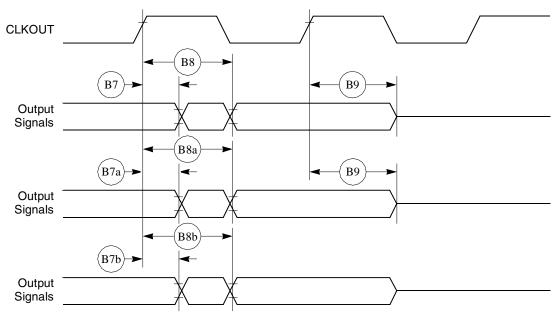


Figure 4. Synchronous Output Signals Timing

Figure 5 provides the timing for the synchronous active pull-up and open-drain output signals.

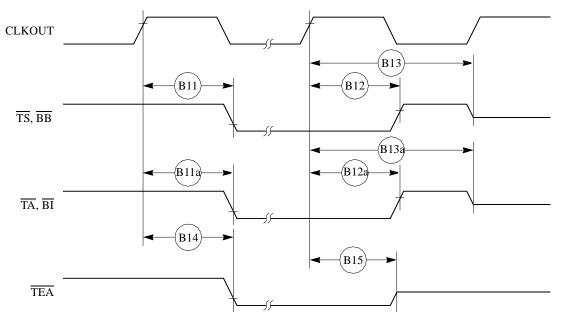


Figure 5. Synchronous Active Pullup and Open-Drain Outputs Signals Timing



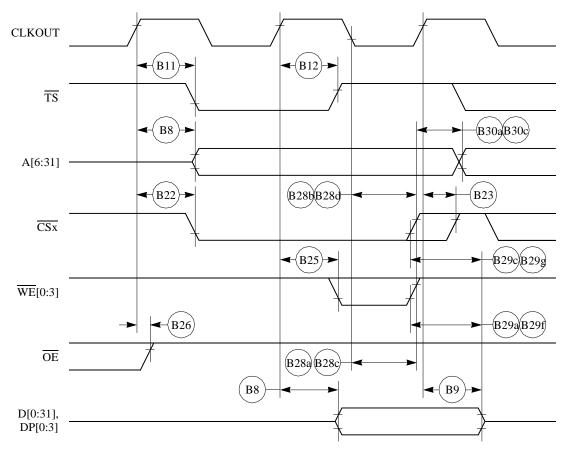
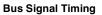


Figure 14. External Bus Write Timing (GPCM Controlled—TRLX = 0, CSNT = 1)





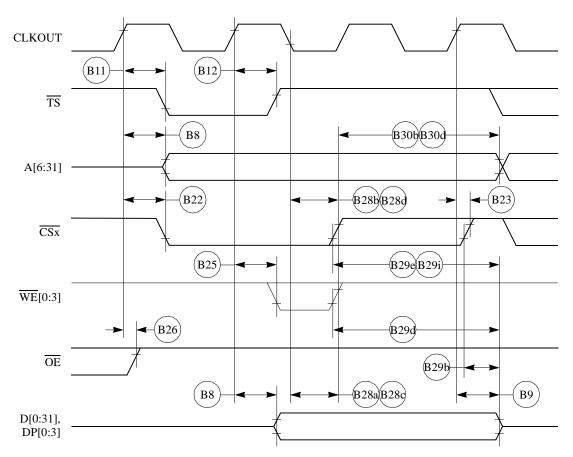


Figure 15. External Bus Write Timing (GPCM Controlled—TRLX = 1, CSNT = 1)



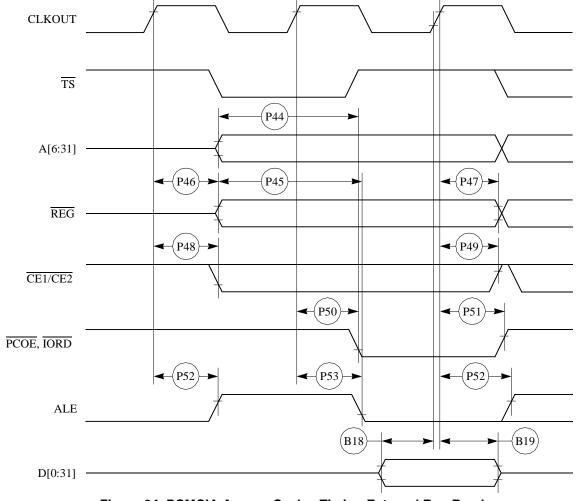


Figure 24 provides the PCMCIA access cycle timing for the external bus read.

Figure 24. PCMCIA Access Cycles Timing External Bus Read



Table 9 shows the PCMCIA port timing for the MPC850.

Table 9. PCMCIA Port Timing

Num	Characteristic		50 MHz		66 MHz		80 MHz	
		Min	Max	Min	Max	Min	Max	Unit
P57	CLKOUT to OPx valid	_	19.00	_	19.00	_	19.00	ns
P58	HRESET negated to OPx drive ¹	18.00	_	26.00	_	22.00	_	ns
P59	IP_Xx valid to CLKOUT rising edge	5.00	_	5.00	_	5.00	_	ns
P60	CLKOUT rising edge to IP_Xx invalid	1.00	_	1.00	_	1.00	_	ns

¹ OP2 and OP3 only.

Figure 27 provides the PCMCIA output port timing for the MPC850.

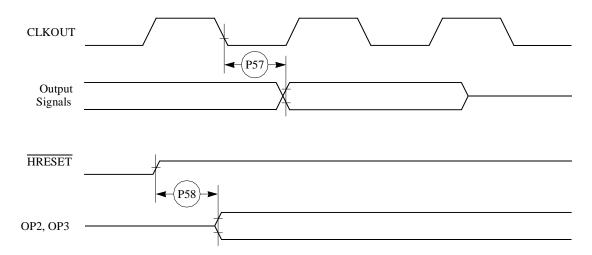


Figure 27. PCMCIA Output Port Timing

Figure 28 provides the PCMCIA output port timing for the MPC850.

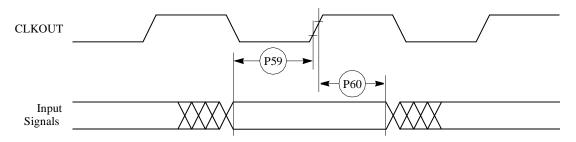


Figure 28. PCMCIA Input Port Timing



Figure 31 shows the reset timing for the data bus configuration.

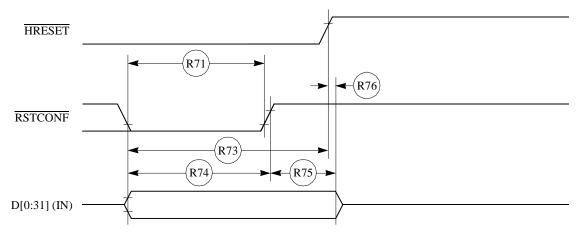


Figure 31. Reset Timing—Configuration from Data Bus

Figure 32 provides the reset timing for the data bus weak drive during configuration.

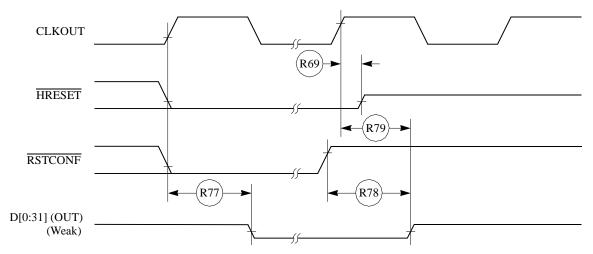


Figure 32. Reset Timing—Data Bus Weak Drive during Configuration



IEEE 1149.1 Electrical Specifications

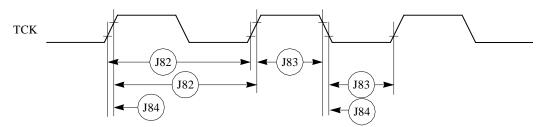


Figure 34. JTAG Test Clock Input Timing

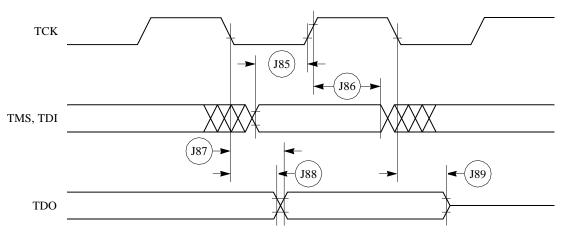


Figure 35. JTAG Test Access Port Timing Diagram

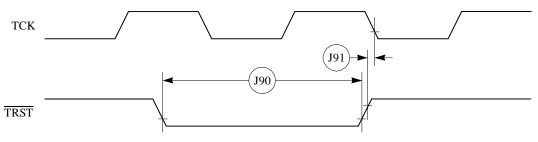
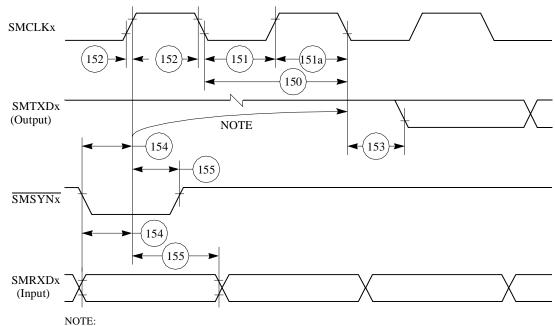


Figure 36. JTAG TRST Timing Diagram





1. This delay is equal to an integer number of character-length clocks.

Figure 56. SMC Transparent Timing Diagram

8.9 SPI Master AC Electrical Specifications

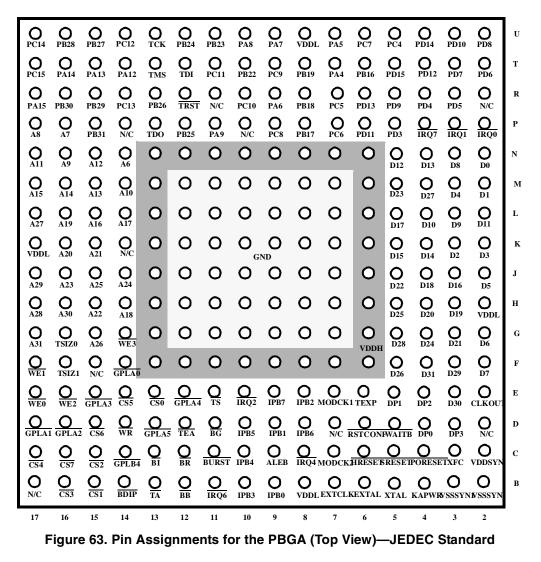
Table 22 provides the SPI master timings as shown in Figure 57 and Figure 58.

Num	Characteristic	All Frequ	Unit	
Num	Characteristic	Min	Max	Unit
160	MASTER cycle time	4	1024	t _{cyc}
161	MASTER clock (SCK) high or low time	2	512	t _{cyc}
162	MASTER data setup time (inputs)	50.00	_	ns
163	Master data hold time (inputs)	0.00	_	ns
164	Master data valid (after SCK edge)	—	20.00	ns
165	Master data hold time (outputs)	0.00	_	ns
166	Rise time output	—	15.00	ns
167	Fall time output	—	15.00	ns

Table 22. SPI Master Timing



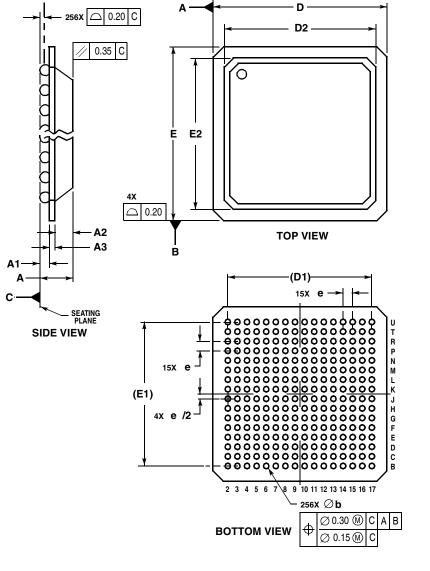
Figure 63 shows the JEDEC pinout of the PBGA package as viewed from the top surface.



For more information on the printed circuit board layout of the PBGA package, including thermal via design and suggested pad layout, please refer to AN-1231/D, Plastic Ball Grid Array Application Note available from your local Freescale sales office.



Figure 65 shows the JEDEC package dimensions of the PBGA.



NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. DIMENSIONS IN MILLIMETERS.
- DIMENSION & IS MEASURED AT THE MAXIMUM SOLDER BALL DIAMETER, PARALLEL TO PRIMARY DATUM C.
- 4. PRIMARY DATUM C AND THE SEATING PLANE ARE

	MILLIMETERS							
DIM	MIN	MAX						
Α	1.91	2.35						
A1	0.50	0.70						
A2	1.12	1.22						
A3	0.29	0.43						
b	0.60	0.90						
D	23.00	BSC						
D1	19.05	REF						
D2	19.00	20.00						
Ε	23.00	BSC						
E1	19.05 REF							
E2	19.00	20.00						
е	1.27	BSC						

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Figure 65. Package Dimensions for the Plastic Ball Grid Array (PBGA)—JEDEC Standard



10 Document Revision History

Table 28 lists significant changes between revisions of this document.

Table 28. Document Revision History

Revision	Date	Change
2	7/2005	Added footnote 3 to Table 5 (previously Table 4.5) and deleted IOL limit.
1	10/2002	Added MPC850DSL. Corrected Figure 25 on page 34.
0.2	04/2002	Updated power numbers and added Rev. C
0.1	11/2001	Removed reference to 5 Volt tolerance capability on peripheral interface pins. Replaced SI and IDL timing diagrams with better images. Updated to new template, added this revision table.



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Japan:

Freescale Semiconductor Japan Ltd. Headquarters ARCO Tower 15F 1-8-1, Shimo-Meguro, Meguro-ku Tokyo 153-0064, Japan 0120 191014 +81 2666 8080 support.japan@freescale.com

Asia/Pacific:

Freescale Semiconductor Hong Kong Ltd. Technical Information Center 2 Dai King Street Tai Po Industrial Estate, Tai Po, N.T., Hong Kong +800 2666 8080 support.asia@freescale.com

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